

**Search Notes**

Application/Control No.

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Examiner

John P. Sheehan

Applicant(s)/Patent under  
Reexamination

TAKASHIMA ET AL.

Art Unit

1793

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR